# E·XFL

### Intel - EPM7192SQC160-10 Datasheet



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#### Understanding <u>Embedded - CPLDs (Complex</u> <u>Programmable Logic Devices)</u>

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixedfunction ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

**Applications of Embedded - CPLDs** 

#### Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	10 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	12
Number of Macrocells	192
Number of Gates	3750
Number of I/O	124
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7192sqc160-10

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MAX 7000 devices contain from 32 to 256 macrocells that are combined into groups of 16 macrocells, called logic array blocks (LABs). Each macrocell has a programmable-AND/fixed-OR array and a configurable register with independently programmable clock, clock enable, clear, and preset functions. To build complex logic functions, each macrocell can be supplemented with both shareable expander product terms and highspeed parallel expander product terms to provide up to 32 product terms per macrocell.

The MAX 7000 family provides programmable speed/power optimization. Speed-critical portions of a design can run at high speed/full power, while the remaining portions run at reduced speed/low power. This speed/power optimization feature enables the designer to configure one or more macrocells to operate at 50% or lower power while adding only a nominal timing delay. MAX 7000E and MAX 7000S devices also provide an option that reduces the slew rate of the output buffers, minimizing noise transients when non-speed-critical signals are switching. The output drivers of all MAX 7000 devices (except 44-pin devices) can be set for either 3.3-V or 5.0-V operation, allowing MAX 7000 devices to be used in mixed-voltage systems.

The MAX 7000 family is supported by Altera development systems, which are integrated packages that offer schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)— and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The software provides EDIF 2 0 0 and 3 0 0, LPM, VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. The software runs on Windows-based PCs, as well as Sun SPARCstation, and HP 9000 Series 700/800 workstations.

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For more information on development tools, see the MAX+PLUS II Programmable Logic Development System & Software Data Sheet and the Quartus Programmable Logic Development System & Software Data Sheet.

# Functional Description

The MAX 7000 architecture includes the following elements:

- Logic array blocks
- Macrocells
- Expander product terms (shareable and parallel)
- Programmable interconnect array
- I/O control blocks

Figure 2 shows the architecture of MAX 7000E and MAX 7000S devices.

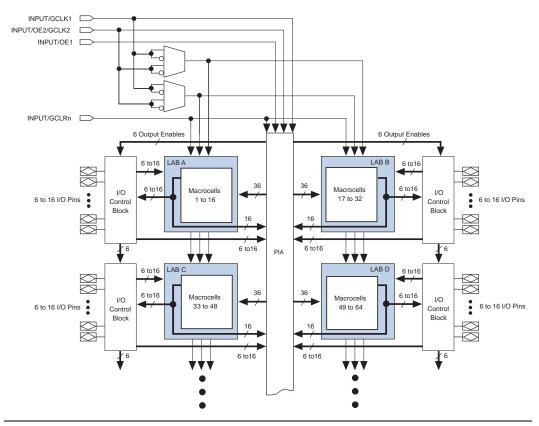
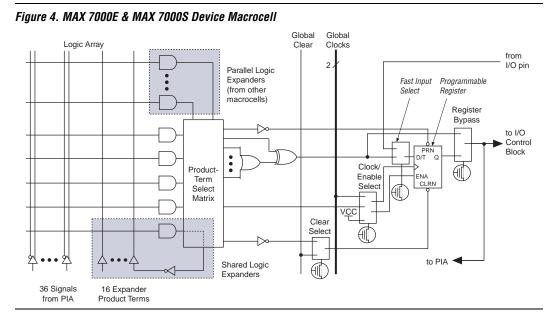
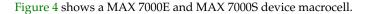


Figure 2. MAX 7000E & MAX 7000S Device Block Diagram

# **Logic Array Blocks**

The MAX 7000 device architecture is based on the linking of highperformance, flexible, logic array modules called logic array blocks (LABs). LABs consist of 16-macrocell arrays, as shown in Figures 1 and 2. Multiple LABs are linked together via the programmable interconnect array (PIA), a global bus that is fed by all dedicated inputs, I/O pins, and macrocells.





Combinatorial logic is implemented in the logic array, which provides five product terms per macrocell. The product-term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register clear, preset, clock, and clock enable control functions. Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

The Altera development system automatically optimizes product-term allocation according to the logic requirements of the design.

For registered functions, each macrocell flipflop can be individually programmed to implement D, T, JK, or SR operation with programmable clock control. The flipflop can be bypassed for combinatorial operation. During design entry, the designer specifies the desired flipflop type; the Altera development software then selects the most efficient flipflop operation for each registered function to optimize resource utilization. The programming times described in Tables 6 through 8 are associated

Device	Progra	mming	Stand-Alone Verification			
	t <sub>PPULSE</sub> (s)	Cycle <sub>PTCK</sub>	t <sub>VPULSE</sub> (s)	Cycle <sub>VTCK</sub>		
EPM7032S	4.02	342,000	0.03	200,000		
EPM7064S	4.50	504,000	0.03	308,000		
EPM7128S	5.11	832,000	0.03	528,000		
EPM7160S	5.35	1,001,000	0.03	640,000		
EPM7192S	5.71	1,192,000	0.03	764,000		
EPM7256S	6.43	1,603,000	0.03	1,024,000		

with the worst-case method using the enhanced ISP algorithm.

Tables 7 and 8 show the in-system programming and stand alone verification times for several common test clock frequencies.

Device		f <sub>TCK</sub>									
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz	]		
EPM7032S	4.06	4.09	4.19	4.36	4.71	5.73	7.44	10.86	s		
EPM7064S	4.55	4.60	4.76	5.01	5.51	7.02	9.54	14.58	S		
EPM7128S	5.19	5.27	5.52	5.94	6.77	9.27	13.43	21.75	s		
EPM7160S	5.45	5.55	5.85	6.35	7.35	10.35	15.36	25.37	S		
EPM7192S	5.83	5.95	6.30	6.90	8.09	11.67	17.63	29.55	S		
EPM7256S	6.59	6.75	7.23	8.03	9.64	14.45	22.46	38.49	S		

Table 8. MAX 7000S Stand-Alone Verification Times for Different Test Clock Frequencies

Device		f <sub>TCK</sub>									
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz			
EPM7032S	0.05	0.07	0.13	0.23	0.43	1.03	2.03	4.03	S		
EPM7064S	0.06	0.09	0.18	0.34	0.64	1.57	3.11	6.19	S		
EPM7128S	0.08	0.14	0.29	0.56	1.09	2.67	5.31	10.59	S		
EPM7160S	0.09	0.16	0.35	0.67	1.31	3.23	6.43	12.83	S		
EPM7192S	0.11	0.18	0.41	0.79	1.56	3.85	7.67	15.31	S		
EPM7256S	0.13	0.24	0.54	1.06	2.08	5.15	10.27	20.51	S		

# IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 7000 devices support JTAG BST circuitry as specified by IEEE Std. 1149.1-1990. Table 9 describes the JTAG instructions supported by the MAX 7000 family. The pin-out tables (see the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin-out information) show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

Table 9. MAX 7000 J	TAG Instructions	5
JTAG Instruction	Devices	Description
SAMPLE/PRELOAD	EPM7128S	Allows a snapshot of signals at the device pins to be captured and
	EPM7160S	examined during normal device operation, and permits an initial data
	EPM7192S	pattern output at the device pins.
	EPM7256S	
EXTEST	EPM7128S	Allows the external circuitry and board-level interconnections to be
	EPM7160S	tested by forcing a test pattern at the output pins and capturing test
	EPM7192S	results at the input pins.
	EPM7256S	
BYPASS	EPM7032S	Places the 1-bit bypass register between the TDI and TDO pins, which
	EPM7064S	allows the BST data to pass synchronously through a selected device
	EPM7128S	to adjacent devices during normal device operation.
	EPM7160S	
	EPM7192S	
	EPM7256S	
IDCODE	EPM7032S	Selects the IDCODE register and places it between TDI and TDO,
	EPM7064S	allowing the IDCODE to be serially shifted out of TDO.
	EPM7128S	
	EPM7160S	
	EPM7192S	
	EPM7256S	
ISP Instructions	EPM7032S	These instructions are used when programming MAX 7000S devices
	EPM7064S	via the JTAG ports with the MasterBlaster, ByteBlasterMV, BitBlaster
	EPM7128S	download cable, or using a Jam File ( <b>.jam</b> ), Jam Byte-Code file ( <b>.jbc</b> ),
	EPM7160S	or Serial Vector Format file (.svf) via an embedded processor or test
	EPM7192S	equipment.
	EPM7256S	

The instruction register length of MAX 7000S devices is 10 bits. Tables 10 and 11 show the boundary-scan register length and device IDCODE information for MAX 7000S devices.

Table 10. MAX 7000S Boundary-S	Scan Register Length
Device	Boundary-Scan Register Length
EPM7032S	1 (1)
EPM7064S	1 (1)
EPM7128S	288
EPM7160S	312
EPM7192S	360
EPM7256S	480

Note:

 This device does not support JTAG boundary-scan testing. Selecting either the EXTEST or SAMPLE/PRELOAD instruction will select the one-bit bypass register.

Table 11. 32	Table 11. 32-Bit MAX 7000 Device IDCODE       Note (1)										
Device		IDCODE (32 B	lits)								
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer's Identity (11 Bits)	<b>1 (1 Bit)</b> (2)							
EPM7032S	0000	0111 0000 0011 0010	00001101110	1							
EPM7064S	0000	0111 0000 0110 0100	00001101110	1							
EPM7128S	0000	0111 0001 0010 1000	00001101110	1							
EPM7160S	0000	0111 0001 0110 0000	00001101110	1							
EPM7192S	0000	0111 0001 1001 0010	00001101110	1							
EPM7256S	0000	0111 0010 0101 0110	00001101110	1							

Notes:

(1) The most significant bit (MSB) is on the left.

(2) The least significant bit (LSB) for all JTAG IDCODEs is 1.

# Operating Conditions

Tables 13 through 18 provide information about absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 5.0-V MAX 7000 devices.

### Table 13. MAX 7000 5.0-V Device Absolute Maximum Ratings Note (1)

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-2.0	7.0	V
VI	DC input voltage		-2.0	7.0	V
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA
T <sub>STG</sub>	Storage temperature	No bias	-65	150	°C
T <sub>AMB</sub>	Ambient temperature	Under bias	-65	135	°C
TJ	Junction temperature	Ceramic packages, under bias		150	°C
		PQFP and RQFP packages, under bias		135	°C

Table 1	4. MAX 7000 5.0-V Device Reco	ommended Operating Conditions			
Symbol	Parameter	Conditions	Min	Мах	Unit
V <sub>CCINT</sub>	input buffers	(3), (4), (5)	4.75 (4.50)	5.25 (5.50)	V
V <sub>CCIO</sub>	Supply voltage for output drivers, 5.0-V operation	(3), (4)	4.75 (4.50)	5.25 (5.50)	V
	Supply voltage for output drivers, 3.3-V operation	(3), (4), (6)	3.00 (3.00)	3.60 (3.60)	V
V <sub>CCISP</sub>	Supply voltage during ISP	(7)	4.75	5.25	V
VI	Input voltage		-0.5 (8)	V <sub>CCINT</sub> + 0.5	V
Vo	Output voltage		0	V <sub>CCIO</sub>	V
T <sub>A</sub>	Ambient temperature	For commercial use	0	5.25 (5.50) 5.25 (5.50) 3.60 (3.60) 5.25 V <sub>CCINT</sub> + 0.5 V <sub>CCIO</sub> 70 85 90 105 40	°C
		For industrial use	-40	85	°C
TJ	Junction temperature	For commercial use	0	90	°C
		For industrial use	-40	105	°C
t <sub>R</sub>	Input rise time			40	ns
t <sub>F</sub>	Input fall time			40	ns

Tables 19 through 26 show the MAX 7000 and MAX 7000E AC  $\,$ operating conditions.

Symbol	Parameter	Conditions	-6 Speed Grade		-7 Spee	Unit	
			Min	Max	Min	Max	ns ns ns ns ns ns ns ns ns ns ns ns ns n
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		6.0		7.5	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		6.0		7.5	ns
t <sub>SU</sub>	Global clock setup time		5.0		6.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	2.5		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.5		0.5		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		4.0		4.5	ns
t <sub>CH</sub>	Global clock high time		2.5		3.0		ns
t <sub>CL</sub>	Global clock low time		2.5		3.0		ns
t <sub>ASU</sub>	Array clock setup time		2.5		3.0		ns
t <sub>AH</sub>	Array clock hold time		2.0		2.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		6.5		7.5	ns
t <sub>ACH</sub>	Array clock high time		3.0		3.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		3.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	3.0		3.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			6.6		8.0	ns
<sup>f</sup> сnт	Maximum internal global clock frequency	(5)	151.5		125.0		MHz
t <sub>ACNT</sub>	Minimum array clock period			6.6		8.0	ns
facnt	Maximum internal array clock frequency	(5)	151.5		125.0		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	200		166.7		MHz

Table 2	9. EPM7064S External Timi	ing Parameters	(Part 2	2 of 2)	No	te (1)					
Symbol	Parameter	Conditions	Speed Grade							Unit	
			-5 -6 -7 -10				0				
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		5.4		6.7		7.5		10.0	ns
t <sub>ACH</sub>	Array clock high time		2.5		2.5		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.5		2.5		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(2)	2.5		2.5		3.0		4.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			5.7		7.1		8.0		10.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(4)	175.4		140.8		125.0		100.0		MHz
t <sub>ACNT</sub>	Minimum array clock period			5.7		7.1		8.0		10.0	ns
f <sub>acnt</sub>	Maximum internal array clock frequency	(4)	175.4		140.8		125.0		100.0		MHz
f <sub>MAX</sub>	Maximum clock frequency	(5)	250.0		200.0		166.7		125.0		MHz

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Table 30. EPM7064S Internal Timing Parameters (Part 1 of 2) Note (1)

Symbol	Parameter	Conditions	Speed Grade								Unit
			-	5	-	6	-	7	-1	10	
			Min	Max	Min	Max	Min	Max	Min	Мах	
t <sub>IN</sub>	Input pad and buffer delay			0.2		0.2		0.5		0.5	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.2		0.2		0.5		0.5	ns
t <sub>FIN</sub>	Fast input delay			2.2		2.6		1.0		1.0	ns
t <sub>SEXP</sub>	Shared expander delay			3.1		3.8		4.0		5.0	ns
t <sub>PEXP</sub>	Parallel expander delay			0.9		1.1		0.8		0.8	ns
t <sub>LAD</sub>	Logic array delay			2.6		3.2		3.0		5.0	ns
t <sub>LAC</sub>	Logic control array delay			2.5		3.2		3.0		5.0	ns
t <sub>IOE</sub>	Internal output enable delay			0.7		0.8		2.0		2.0	ns
t <sub>OD1</sub>	Output buffer and pad delay	C1 = 35 pF		0.2		0.3		2.0		1.5	ns
t <sub>OD2</sub>	Output buffer and pad delay	C1 = 35 pF (6)		0.7		0.8		2.5		2.0	ns
t <sub>OD3</sub>	Output buffer and pad delay	C1 = 35 pF		5.2		5.3		7.0		5.5	ns
t <sub>ZX1</sub>	Output buffer enable delay	C1 = 35 pF		4.0		4.0		4.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		4.5		5.5	ns
t <sub>ZX3</sub>	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		9.0	ns
t <sub>XZ</sub>	Output buffer disable delay	C1 = 5 pF		4.0		4.0		4.0		5.0	ns
t <sub>SU</sub>	Register setup time		0.8		1.0		3.0		2.0		ns
t <sub>H</sub>	Register hold time		1.7		2.0		2.0		3.0		ns

Table 3	0. EPM7064S Internal Tir	ning Parameters	s (Part à	2 of 2)	No	te (1)					
Symbol	Parameter	Conditions	Conditions Speed Grade								Unit
			-	5	-	6	-	7	-1	10	
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>FSU</sub>	Register setup time of fast input		1.9		1.8		3.0		3.0		ns
t <sub>FH</sub>	Register hold time of fast input		0.6		0.7		0.5		0.5		ns
t <sub>RD</sub>	Register delay			1.2		1.6		1.0		2.0	ns
t <sub>COMB</sub>	Combinatorial delay			0.9		1.0		1.0		2.0	ns
t <sub>IC</sub>	Array clock delay			2.7		3.3		3.0		5.0	ns
t <sub>EN</sub>	Register enable time			2.6		3.2		3.0		5.0	ns
t <sub>GLOB</sub>	Global control delay			1.6		1.9		1.0		1.0	ns
t <sub>PRE</sub>	Register preset time			2.0		2.4		2.0		3.0	ns
t <sub>CLR</sub>	Register clear time			2.0		2.4		2.0		3.0	ns
t <sub>PIA</sub>	PIA delay	(7)		1.1		1.3		1.0		1.0	ns
t <sub>LPA</sub>	Low-power adder	(8)		12.0		11.0		10.0		11.0	ns

#### Notes to tables:

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t<sub>LPA</sub> parameter must be added to this minimum width if the clear or reset signal incorporates the t<sub>LAD</sub> parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3 \text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters for macrocells running in the low-power mode.

#### Notes to tables:

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t<sub>LPA</sub> parameter must be added to this minimum width if the clear or reset signal incorporates the t<sub>LAD</sub> parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3 \text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters for macrocells running in the low-power mode.

#### Tables 33 and 34 show the EPM7160S AC operating conditions.

Symbol	Parameter	Conditions				Speed	Grade	)			Unit
			-6		-	7	-10		-15		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		6.0		7.5		10.0		15.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		6.0		7.5		10.0		15.0	ns
t <sub>SU</sub>	Global clock setup time		3.4		4.2		7.0		11.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.5		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		3.9		4.8		5		8	ns
t <sub>CH</sub>	Global clock high time		3.0		3.0		4.0		5.0		ns
t <sub>CL</sub>	Global clock low time		3.0		3.0		4.0		5.0		ns
t <sub>ASU</sub>	Array clock setup time		0.9		1.1		2.0		4.0		ns
t <sub>AH</sub>	Array clock hold time		1.7		2.1		3.0		4.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		6.4		7.9		10.0		15.0	ns
t <sub>ACH</sub>	Array clock high time		3.0		3.0		4.0		6.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		3.0		4.0		6.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(2)	2.5		3.0		4.0		6.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF <i>(3)</i>	1.0		1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			6.7		8.2		10.0		13.0	ns
f <sub>сnт</sub>	Maximum internal global clock frequency	(4)	149.3		122.0		100.0		76.9		MHz

**Altera Corporation** 

Table 3	3. EPM7160S External Time	ing Parameters	(Part 2	2 of 2)	No	nte (1)					
Symbol	Parameter	Conditions				Speed	Grade	)			Unit
			-	6	-	7	-1	0	-1	5	
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>ACNT</sub>	Minimum array clock period			6.7		8.2		10.0		13.0	ns
f <sub>acnt</sub>	Maximum internal array clock frequency	(4)	149.3		122.0		100.0		76.9		MHz
f <sub>MAX</sub>	Maximum clock frequency	(5)	166.7		166.7		125.0		100.0		MHz

Symbol	Parameter	Conditions				Speed	Grade				Unit
			-	6	-	7	-1	10	-1	15	
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>IN</sub>	Input pad and buffer delay			0.2		0.3		0.5		2.0	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.2		0.3		0.5		2.0	ns
t <sub>FIN</sub>	Fast input delay			2.6		3.2		1.0		2.0	ns
t <sub>SEXP</sub>	Shared expander delay			3.6		4.3		5.0		8.0	ns
t <sub>PEXP</sub>	Parallel expander delay			1.0		1.3		0.8		1.0	ns
t <sub>LAD</sub>	Logic array delay			2.8		3.4		5.0		6.0	ns
t <sub>LAC</sub>	Logic control array delay			2.8		3.4		5.0		6.0	ns
t <sub>IOE</sub>	Internal output enable delay			0.7		0.9		2.0		3.0	ns
t <sub>OD1</sub>	Output buffer and pad delay	C1 = 35 pF		0.4		0.5		1.5		4.0	ns
t <sub>OD2</sub>	Output buffer and pad delay	C1 = 35 pF (6)		0.9		1.0		2.0		5.0	ns
t <sub>OD3</sub>	Output buffer and pad delay	C1 = 35 pF		5.4		5.5		5.5		8.0	ns
t <sub>ZX1</sub>	Output buffer enable delay	C1 = 35 pF		4.0		4.0		5.0		6.0	ns
t <sub>ZX2</sub>	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		5.5		7.0	ns
t <sub>ZX3</sub>	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		10.0	ns
t <sub>XZ</sub>	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0		6.0	ns
t <sub>SU</sub>	Register setup time		1.0		1.2		2.0		4.0		ns
t <sub>H</sub>	Register hold time		1.6		2.0		3.0		4.0		ns
t <sub>FSU</sub>	Register setup time of fast input		1.9		2.2		3.0		2.0		ns
t <sub>FH</sub>	Register hold time of fast input		0.6		0.8		0.5		1.0		ns
t <sub>RD</sub>	Register delay			1.3		1.6		2.0		1.0	ns
t <sub>COMB</sub>	Combinatorial delay			1.0		1.3		2.0		1.0	ns
t <sub>IC</sub>	Array clock delay			2.9		3.5		5.0		6.0	ns
t <sub>EN</sub>	Register enable time			2.8		3.4		5.0		6.0	ns
t <sub>GLOB</sub>	Global control delay			2.0		2.4		1.0		1.0	ns
t <sub>PRE</sub>	Register preset time			2.4		3.0		3.0		4.0	ns

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Symbol	Parameter	Conditions			Speed	Grade			Unit
			-7		-10		-15		1
			Min	Мах	Min	Max	Min	Max	
t <sub>AH</sub>	Array clock hold time		1.8		3.0		4.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		7.8		10.0		15.0	ns
t <sub>ACH</sub>	Array clock high time		3.0		4.0		6.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		4.0		6.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(2)	3.0		4.0		6.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			8.0		10.0		13.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(4)	125.0		100.0		76.9		MHz
t <sub>ACNT</sub>	Minimum array clock period			8.0		10.0		13.0	ns
f <sub>acnt</sub>	Maximum internal array clock frequency	(4)	125.0		100.0		76.9		MHz
f <sub>MAX</sub>	Maximum clock frequency	(5)	166.7		125.0		100.0		MHz

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Table 3	6. EPM7192S Internal Tim	ing Parameters (Pa	rt 1 of 2)	Note	(1)						
Symbol	Parameter	Conditions		Speed Grade							
			-	-7		-10		15			
			Min	Max	Min	Max	Min	Max			
t <sub>IN</sub>	Input pad and buffer delay			0.3		0.5		2.0	ns		
t <sub>IO</sub>	I/O input pad and buffer delay			0.3		0.5		2.0	ns		
t <sub>FIN</sub>	Fast input delay			3.2		1.0		2.0	ns		
t <sub>SEXP</sub>	Shared expander delay			4.2		5.0		8.0	ns		
t <sub>PEXP</sub>	Parallel expander delay			1.2		0.8		1.0	ns		
t <sub>LAD</sub>	Logic array delay			3.1		5.0		6.0	ns		
t <sub>LAC</sub>	Logic control array delay			3.1		5.0		6.0	ns		
t <sub>IOE</sub>	Internal output enable delay			0.9		2.0		3.0	ns		
t <sub>OD1</sub>	Output buffer and pad delay	C1 = 35 pF		0.5		1.5		4.0	ns		
t <sub>OD2</sub>	Output buffer and pad delay	C1 = 35 pF (6)		1.0		2.0		5.0	ns		
t <sub>OD3</sub>	Output buffer and pad delay	C1 = 35 pF		5.5		5.5		7.0	ns		
t <sub>ZX1</sub>	Output buffer enable delay	C1 = 35 pF		4.0		5.0		6.0	ns		
t <sub>ZX2</sub>	Output buffer enable delay	C1 = 35 pF (6)		4.5		5.5		7.0	ns		
t <sub>ZX3</sub>	Output buffer enable delay	C1 = 35 pF		9.0		9.0		10.0	ns		
t <sub>XZ</sub>	Output buffer disable delay	C1 = 5 pF		4.0		5.0		6.0	ns		
t <sub>SU</sub>	Register setup time		1.1		2.0		4.0		ns		

Symbol	Parameter	Conditions			Speed	Grade			Unit
			-7		-10		-1	5	
			Min	Max	Min	Max	Min	Max	
t <sub>H</sub>	Register hold time		1.7		3.0		4.0		ns
t <sub>FSU</sub>	Register setup time of fast input		2.3		3.0		2.0		ns
t <sub>FH</sub>	Register hold time of fast input		0.7		0.5		1.0		ns
t <sub>RD</sub>	Register delay			1.4		2.0		1.0	ns
t <sub>COMB</sub>	Combinatorial delay			1.2		2.0		1.0	ns
t <sub>IC</sub>	Array clock delay			3.2		5.0		6.0	ns
t <sub>EN</sub>	Register enable time			3.1		5.0		6.0	ns
t <sub>GLOB</sub>	Global control delay			2.5		1.0		1.0	ns
t <sub>PRE</sub>	Register preset time			2.7		3.0		4.0	ns
t <sub>CLR</sub>	Register clear time			2.7		3.0		4.0	ns
t <sub>PIA</sub>	PIA delay	(7)		2.4		1.0		2.0	ns
t <sub>LPA</sub>	Low-power adder	(8)		10.0		11.0		13.0	ns

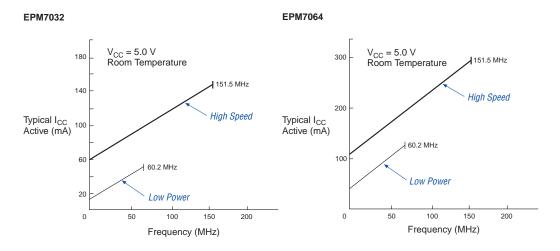
#### Notes to tables:

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t<sub>LPA</sub> parameter must be added to this minimum width if the clear or reset signal incorporates the t<sub>LAD</sub> parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3 \text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters for macrocells running in the low-power mode.

Table 39. MAX 7000 I <sub>CC</sub> Equation Constants									
Device	A	В	C						
EPM7032	1.87	0.52	0.144						
EPM7064	1.63	0.74	0.144						
EPM7096	1.63	0.74	0.144						
EPM7128E	1.17	0.54	0.096						
EPM7160E	1.17	0.54	0.096						
EPM7192E	1.17	0.54	0.096						
EPM7256E	1.17	0.54	0.096						
EPM7032S	0.93	0.40	0.040						
EPM7064S	0.93	0.40	0.040						
EPM7128S	0.93	0.40	0.040						
EPM7160S	0.93	0.40	0.040						
EPM7192S	0.93	0.40	0.040						
EPM7256S	0.93	0.40	0.040						

This calculation provides an  $I_{CC}$  estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual  $I_{CC}$  values should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions. Figure 14 shows typical supply current versus frequency for MAX 7000 devices.





EPM7096

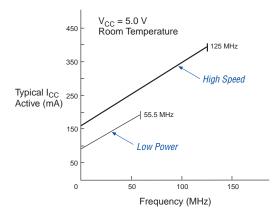
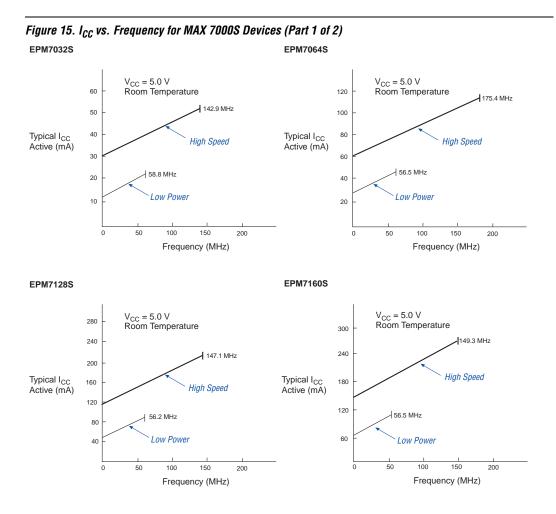
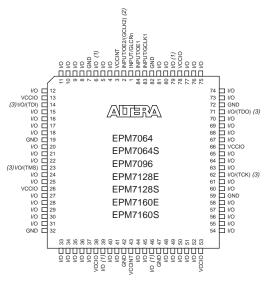


Figure 15 shows typical supply current versus frequency for MAX 7000S devices.



#### Figure 18. 84-Pin Package Pin-Out Diagram

Package outline not drawn to scale.



84-Pin PLCC

Notes:

- (1) Pins 6, 39, 46, and 79 are no-connect (N.C.) pins on EPM7096, EPM7160E, and EPM7160S devices.
- (2) The pin functions shown in parenthesis are only available in MAX 7000E and MAX 7000S devices.
- (3) JTAG ports are available in MAX 7000S devices only.

# Revision History

The information contained in the *MAX 7000 Programmable Logic Device Family Data Sheet* version 6.7 supersedes information published in previous versions. The following changes were made in the *MAX 7000 Programmable Logic Device Family Data Sheet* version 6.7:

# Version 6.7

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.7:

Reference to AN 88: Using the Jam Language for ISP & ICR via an Embedded Processor has been replaced by AN 122: Using Jam STAPL for ISP & ICR via an Embedded Processor.

## Version 6.6

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.6:

- Added Tables 6 through 8.
- Added "Programming Sequence" section on page 17 and "Programming Times" section on page 18.

## Version 6.5

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.5:

Updated text on page 16.

### Version 6.4

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.4:

Added Note (5) on page 28.

### Version 6.3

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.3:

 Updated the "Open-Drain Output Option (MAX 7000S Devices Only)" section on page 20.

